

# Chase-like Decoding: Test Pattern Design and Performance Analysis

Tim Janz, Simon Obermüller, Andreas Zunker, and Stephan ten Brink  
Institute of Telecommunications, University of Stuttgart, Germany  
{janz, obermueller, zunker, tenbrink}@inue.uni-stuttgart.de

**Abstract**—Chase-like decoding algorithms are a popular choice for soft-input decoding of algebraic codes. In this paper, we evaluate the performance of different test pattern sets using three methods. For test pattern sets with a certain structure such as Chase-II test patterns and patterns up to a maximum logistic weight, we use a method that relies on order statistics. The performance of arbitrary sets of test patterns is evaluated by calculating covered space probabilities and via direct Monte Carlo simulation. Based on the idea of covering as many likely error patterns as possible, we propose an algorithm for the design of test pattern sets which perform up to 0.2 dB better for high-rate BCH codes than commonly used test pattern sets.

## I. INTRODUCTION

Due to their good minimum distance and efficient decodability, binary Bose–Ray–Chaudhuri–Hocquenghem (BCH) [1], [2] codes are widely used in communication systems [3]. They are often used in concatenated coding schemes [4] to further improve the performance without significantly impacting latency or complexity, e.g., for data center interconnects and the next Ethernet standard together with a KP4 (544,514) Reed–Solomon (RS) outer code [5]. BCH codes are also employed in long-haul optical communication schemes as the component codes of generalized product codes [6]–[8] such as oFEC [9].

For BCH codes, the performance of hard-decision decoding with a bounded-distance decoder (BDD) has a large gap to maximum likelihood (ML) decoding. To improve the performance, BCH codes are often decoded with soft-input decoders, either with hard-output, as for concatenated schemes with hard-input outer codes, or with soft-output to iterate between component codes as in turbo product decoding (TPD) [10].

For both cases, the Chase-II algorithm is a commonly used decoder [11]. Given a channel output, it generates a list of candidate codewords  $\mathcal{L}$  from decoding  $2^p$  testwords with a BDD. In the context of guessing random additive noise decoding (GRAND), patterns based on their logistic weight were introduced [12]. They can also be used in a Chase-like decoder and show good performance [13]. Only few works suggest alternative test pattern sets such as [14], [15], where test patterns for medium-rate BCH codes were designed using covering codes [16].

The performance of Chase-II decoding and generalized minimum distance (GMD) decoding [17] were analyzed in [18]–[20]. A thorough comparison of the performance of different sets of patterns, especially for high-rate BCH codes, is, to the best of our knowledge, still missing.

In this paper, we present three methods to determine the list error rate (LER), i.e., the probability that the sent codeword is not in the list generated by the Chase-like decoder, and show that they give equivalent results. The first method uses order statistics and was introduced in [19] based on [18]. We extend the method to Chase-II patterns of restricted Hamming weight and patterns with a maximum logistic weight. The second method uses the calculation of the covered space as suggested in [21] to calculate the LER of arbitrary patterns. The third method is a Monte Carlo simulation of the transmission system.

Furthermore, we introduce a design algorithm for test pattern sets that achieve almost the same performance as test patterns found by a greedy approach. The test pattern sets from our suggested design gain up to 0.2 dB in terms of block error rate (BLER) compared to the commonly used Chase-II patterns of restricted Hamming weight.

## II. PRELIMINARIES

Let  $[n] \triangleq \{1, 2, \dots, n\}$  and  $[m, n] \triangleq \{m, m+1, \dots, n\}$  for  $m < n$  with  $n \in \mathbb{N}$  and  $m \in \mathbb{N}_0$ . We denote the power set of an index set  $\mathcal{K} \subseteq [n]$  as  $\mathcal{P}_{\mathcal{K}}$  with  $|\mathcal{P}_{\mathcal{K}}| = 2^{|\mathcal{K}|}$ . The subvector of  $\mathbf{v} \in \mathbb{F}_2^n$  containing only the elements at positions  $\mathcal{K} \subseteq [n]$  of  $\mathbf{v}$  is given by  $\mathbf{v}_{\mathcal{K}} \in \mathbb{F}_2^{|\mathcal{K}|}$ . The vector of length  $n$  with ones at positions  $\mathcal{K} \subseteq [n]$  and zeros at positions  $[n] \setminus \mathcal{K}$  is denoted by  $\mathbf{1}_{\mathcal{K}}$ . For a vector  $\mathbf{u} \in \mathbb{F}_2^n$ , the set of positions equal to one is  $\mathcal{I}_{\mathbf{u}}$  and  $i_{\mathbf{u}}^{\max} = \max(\mathcal{I}_{\mathbf{u}})$ . Let  $\mathbf{u} \oplus \mathbf{v}$  be the element-wise addition over  $\mathbb{F}_2$  for two vectors  $\mathbf{u}, \mathbf{v} \in \mathbb{F}_2^n$ . The Hamming weight of a vector  $\mathbf{u} \in \mathbb{F}_2^n$  and the Hamming distance of the vectors  $\mathbf{u}, \mathbf{v} \in \mathbb{F}_2^n$  are denoted by  $w_{\text{H}}(\mathbf{u})$  and  $d_{\text{H}}(\mathbf{u}, \mathbf{v})$ , respectively. Let  $\mathcal{B}_r(\mathbf{u}) \triangleq \{\mathbf{v} \in \mathbb{F}_2^n \mid d_{\text{H}}(\mathbf{u}, \mathbf{v}) \leq r\}$  be the Hamming ball of radius  $r$  that is centered at  $\mathbf{u}$ . The logistic weight of a vector  $\mathbf{u}$  is defined as  $w_{\text{L}}(\mathbf{u}) = \sum_{i=1}^n i u_i$ .

### A. Channel Model

We consider transmission over a binary-input additive white Gaussian noise (BI-AWGN) channel  $Y = X + Z$ , where  $Z \sim \mathcal{N}(0, \sigma^2)$  and  $X \in \{+1, -1\}$  is the binary phase shift keying (BPSK) modulated channel input with  $0 \mapsto +1$  and  $1 \mapsto -1$ .

As channel codes, we use  $(n, k, t)$  primitive, narrow-sense, binary BCH codes of length  $n$ , dimension  $k$  and error correction capability  $t = \lfloor \frac{d_{\text{des}} - 1}{2} \rfloor$ , where the design distance  $d_{\text{des}}$  is a lower bound on the minimum distance  $d_{\text{min}}$ .

For a given channel output  $\mathbf{y} \in \mathbb{R}^n$ , we can compute the channel log-likelihood ratio (LLR) as  $\boldsymbol{\ell} = \frac{2}{\sigma^2} \mathbf{y}$  and define the reliability as  $\alpha \triangleq |\boldsymbol{\ell}|$ . Throughout this paper, we assume that the received channel output is already sorted with respect to the corresponding reliabilities such that  $\alpha_1 \leq \alpha_2 \leq \dots \leq \alpha_n$ . The hard decision is denoted by  $\hat{\mathbf{y}}$ , where  $\hat{y}_i = 1$  for  $y_i < 0$  and  $\hat{y}_i = 0$  otherwise.

For a transmitted codeword  $\mathbf{c} \in \mathbb{F}_2^n$ , the error vector is given by  $\mathbf{e} = \mathbf{c} \oplus \hat{\mathbf{y}}$ . Let  $\mathcal{E}_b$  denote the event that the hard decision is erroneous at  $b$  positions. For the BI-AWGN channel, the probability of  $b$  bit flips is

$$P(\mathcal{E}_b) = \binom{n}{b} [1 - Q(1/\sigma)]^b Q(1/\sigma)^{n-b}, \quad (1)$$

with  $Q(\cdot)$  being the tail distribution function of  $\mathcal{N}(0, 1)$ .

For a BDD with error correction capability  $t$ , the probability that the transmitted codeword is decoded correctly can be calculated by

$$P_{\text{BDD}} \triangleq P_{\text{BDD}}(\hat{\mathbf{c}} = \mathbf{c}) = \sum_{i=0}^t P(\mathcal{E}_i). \quad (2)$$

### B. Chase-like Decoding

A popular approach for incorporating soft information into hard-decision decoding is the Chase-II algorithm [11]. More generally, a Chase-like algorithm with a predetermined test pattern set  $\mathcal{R}$  operates as follows.

First, the hard-decision vector  $\hat{\mathbf{y}} = (\hat{y}_1, \dots, \hat{y}_n)$  is formed. The corresponding set of testwords is  $\mathcal{T} = \{\hat{\mathbf{y}} \oplus \boldsymbol{\rho} \mid \boldsymbol{\rho} \in \mathcal{R}\}$ , where  $\mathcal{R}$  is the set of test patterns with cardinality  $q \triangleq |\mathcal{R}|$ . Each testword  $\boldsymbol{\tau} \in \mathcal{T}$  is then decoded by a BDD, and the obtained unique codewords form the candidate list  $\mathcal{L}$ . For hard-output decoding, the most likely codeword is selected as  $\hat{\mathbf{c}} = \arg \max_{\mathbf{c}' \in \mathcal{L}} P(\mathbf{c}' \mid \mathbf{y})$ . Alternatively, the remaining list candidates can be used to generate soft outputs [10], [21].

Chase-like algorithms differ in the choice of the test pattern set  $\mathcal{R}$ . The Chase-II algorithm considers all  $2^p$  bit flips within the  $p$  least reliable positions with  $\mathcal{R}_{\text{Chase}} = \{\mathbf{1}_{\mathcal{K}} \mid \mathcal{K} \in \mathcal{P}_{[p]}\}$ . A common alternative that restricts the patterns to at most  $w_{\text{H}}^{\text{max}}$  bits among the  $p$  least reliable positions is the *restricted Chase pattern set*  $\mathcal{R}_{\text{restr}} = \{\mathbf{1}_{\mathcal{K}} \mid \mathcal{K} \in \mathcal{P}_{[p]}, |\mathcal{K}| \leq w_{\text{H}}^{\text{max}}\}$ .

Recently, patterns ordered by increasing logistic weight (LW) were proposed for GRAND [12]. We refer to them as *logistic weight patterns*  $\mathcal{R}_{\text{LW}}$  and define them as follows.

**Definition 1** (Logistic Weight Patterns). The logistic weight pattern set  $\mathcal{R}_{\text{LW}}$  of cardinality  $q$  contains the  $q$  patterns with smallest logistic weight. Ties are broken by Hamming weight and then, if necessary, by smaller binary representation.

### C. Error Probability of Chase-like Decoding

The error probability of a Chase-like decoding algorithm with test pattern set  $\mathcal{R} \subseteq \mathbb{F}_2^n$  can be decomposed as

$$\begin{aligned} P_{\mathcal{R}}(\hat{\mathbf{c}} \neq \mathbf{c}) &= P_{\mathcal{R}}(\hat{\mathbf{c}} \neq \mathbf{c}, \mathbf{c} \in \mathcal{L}) + P_{\mathcal{R}}(\hat{\mathbf{c}} \neq \mathbf{c}, \mathbf{c} \notin \mathcal{L}) \\ &\stackrel{(a)}{=} P_{\mathcal{R}}(\hat{\mathbf{c}} \neq \mathbf{c}, \mathbf{c} \in \mathcal{L}) + P_{\mathcal{R}}(\mathbf{c} \notin \mathcal{L}) \\ &\stackrel{(b)}{\leq} P(\mathbf{c}_{\text{ML}} \neq \mathbf{c}) + P_{\mathcal{R}}(\mathbf{c} \notin \mathcal{L}), \end{aligned}$$

where (a) follows since  $\hat{\mathbf{c}} \in \mathcal{L}$  always holds, and (b) follows because the term  $P_{\mathcal{R}}(\hat{\mathbf{c}} \neq \mathbf{c}, \mathbf{c} \in \mathcal{L})$  is maximized for  $\mathcal{L} = \mathcal{C}$ , yielding the BLER of ML decoding. We call  $P_{\mathcal{R}}(\mathbf{c} \notin \mathcal{L})$  the list error rate (LER), which provides a tight approximation of the BLER for  $P(\mathbf{c}_{\text{ML}} \neq \mathbf{c}) \ll P_{\mathcal{R}}(\mathbf{c} \notin \mathcal{L})$  [18], [19].

### D. Covered Space Probability Calculation

For the probability  $P(\mathbf{v} \mid \mathbf{y})$  that a vector  $\mathbf{v}$  was transmitted given the received vector  $\mathbf{y}$ , without considering codebook information, we obtain

$$P(\mathbf{v} \mid \mathbf{y}) = \prod_{i: v_i = \hat{y}_i} \gamma_i \cdot \prod_{i: v_i \neq \hat{y}_i} (1 - \gamma_i),$$

with  $\gamma_i = P(v_i = \hat{y}_i \mid y_i) = \frac{1}{1 + e^{-\ell_i}}$ . This probability should not be confused with the codebook-aware posterior probability  $P(\mathbf{c} \mid \mathbf{y})$ , which is only non-zero for  $\mathbf{c} \in \mathcal{C}$  and not considered in this paper.

The subset of the ambient space  $\mathbb{F}_2^n$  that is explored for codewords by a Chase-like algorithm is called the *covered space*  $\mathcal{V}$  as in [21]. For Chase-like decoding, it is given by

$$\mathcal{V} = \bigcup_{\boldsymbol{\rho} \in \mathcal{R}} \mathcal{B}_t(\boldsymbol{\rho}).$$

The probability of the covered space is defined as

$$P_{\text{cov}}(\mathbf{y}) = \sum_{\mathbf{v} \in \mathcal{V}} P(\mathbf{v} \mid \mathbf{y}) = P(\mathbf{c} \in \mathcal{L} \mid \mathbf{y}),$$

which coincides with the probability that the transmitted codeword  $\mathbf{c}$  is in the list  $\mathcal{L}$  found by the Chase-like algorithm, since  $\mathcal{L} = \mathcal{V} \cap \mathcal{C}$ . An efficient way for evaluating  $P_{\text{cov}}(\mathbf{y})$  for the Chase-II algorithm using Hamming balls is given in [21].

## III. PERFORMANCE EVALUATION METHODS

In the following, we discuss three methods to evaluate the LERs for given sets of test patterns.

For this, it is helpful to quantify the contribution of a test pattern set  $\mathcal{R}'$  that is added to a set of patterns  $\mathcal{R}$  as

$$P_{\mathcal{R}}^{\text{add}}(\mathcal{R}') \triangleq P_{\mathcal{R} \cup \mathcal{R}'}(\mathbf{c} \in \mathcal{L}) - P_{\mathcal{R}}(\mathbf{c} \in \mathcal{L}).$$

With slight abuse of notation, the probability added by a single test pattern  $\boldsymbol{\rho}$  is denoted as  $P_{\mathcal{R}}^{\text{add}}(\boldsymbol{\rho}) = P_{\mathcal{R}}^{\text{add}}(\{\boldsymbol{\rho}\})$ .

### A. List Error Rate with Order Statistics

Instead of calculating  $P_{\mathcal{R}}(\mathbf{c} \notin \mathcal{L})$  directly as in [19], we consider the complementary probability  $P_{\mathcal{R}}(\mathbf{c} \in \mathcal{L})$ . The computations are based on the order statistics of the channel model. However, we give an abstract description of the probabilities that need to be calculated. The computations of the abstracted probabilities with order statistics are described in Appendix A.

The result for the Chase-II algorithm can be derived by considering the error vectors which are covered in addition to the BDD. The set of test patterns  $\mathcal{R}_{\text{Chase}}$  can be split into disjoint subsets of patterns with the same Hamming weight, i.e.,  $\mathcal{R}_{\text{Chase}} = \bigcup_{w=0}^p \mathcal{R}_w$  with  $\mathcal{R}_w = \{\mathbf{1}_{\mathcal{K}} \mid \mathcal{K} \in \mathcal{P}_{[p]}, |\mathcal{K}| = w\}$ . The union of all test patterns up to weight  $w$  is labeled

as  $\mathcal{R}_{[0,w]} \triangleq \bigcup_{i \in [0,w]} \mathcal{R}_i$ . They form the pattern set of the restricted Chase algorithm. The error vectors covered by the test patterns  $\rho \in \mathcal{R}_w$  in addition to the vectors already covered by  $\mathcal{R}_{[0,w-1]}$  are those with  $w$  flips in the  $p$  least reliable positions and up to  $t$  additional flips in the  $n-p$  most reliable positions. Thus, we have

$$P_{\mathcal{R}_{[0,w-1]}}^{\text{add}}(\mathcal{R}_w) = P(w_{\text{H}}(e_{[p]}) = w | \mathcal{E}_{t+w})P(\mathcal{E}_{t+w}).$$

Overall, the probability that the transmitted codeword is in the list for Chase-II decoding is given by

$$P_{\text{Chase}}(c \in \mathcal{L}) = P_{\text{BDD}} + \sum_{i=t+1}^{p+t} P(w_{\text{H}}(e_{[p]}) = i-t | \mathcal{E}_i)P(\mathcal{E}_i), \quad (3)$$

in accordance with [19]. For the restricted Chase algorithm, the set of test patterns  $\mathcal{R}_{\text{restr}}$  contains only those patterns with Hamming weight at most  $w_{\text{H}}^{\text{max}}$ . Thus, the probability that the transmitted codeword is in the list generated by the restricted Chase algorithm can be calculated by

$$P_{\text{restr}}(c \in \mathcal{L}) = P_{\text{BDD}} + \sum_{i=t+1}^{w_{\text{H}}^{\text{max}}+t} P(w_{\text{H}}(e_{[p]}) = i-t | \mathcal{E}_i)P(\mathcal{E}_i). \quad (4)$$

In the following, we will derive a way to calculate the LER of Chase-like decoding with logistic weight patterns  $\mathcal{R}_{\text{LW}}$  as defined in Definition 1, for which the following property will be of use.

**Property 1.** For a fixed logistic weight pattern  $\rho \in \mathcal{R}_{\text{LW}}$  as defined in Definition 1, it holds  $\{\mathbf{1}_{\mathcal{K}} | \mathcal{K} \in \mathcal{P}_{\mathcal{I}_{\rho}} \setminus \emptyset\} \subseteq \mathcal{R}_{\text{LW}}$ .

*Remark.* Property 1 coincides with a useful trick for an efficient sequential implementation of Chase-like algorithms. A pattern  $\rho'$  with a difference in only one position  $i$  to the current pattern  $\rho$  was already decoded. The syndrome does not need to be computed again, but it is sufficient to reuse the syndrome form the test word of pattern  $\rho'$  and only exclusive-or the syndrome contribution of the  $i$ -th position. This reduces the number of calculations significantly.

We can now consider which additional error vectors are covered by a pattern  $\rho \in \mathcal{R}_{\text{LW}}$ .

**Lemma 1.** Let  $\mathcal{R}_{\text{LW}}$  be the set of logistic weight patterns as in Definition 1. The logistic weight pattern  $\rho$  covers, in addition to  $\mathcal{R}_{\text{LW}} \setminus \{\rho\}$ , all vectors with errors at positions  $\mathcal{I}_{\rho}$  and at most  $t$  further errors at positions  $i \in [i_{\rho}^{\text{max}} + 1, n]$ .

*Proof:* The set of error vectors covered by the pattern  $\rho$  is  $\mathcal{V} = \{\rho \oplus \mathbf{1}_{\mathcal{K}} | \mathcal{K} \in \mathcal{P}_{[n]}, |\mathcal{K}| \leq t\}$ . It suffices to show that all error vectors of  $\mathcal{V}$  are already covered except the subset  $\mathcal{V}_1 = \{\rho \oplus \mathbf{1}_{\mathcal{K}} | \mathcal{K} \in \mathcal{P}_{[i_{\rho}^{\text{max}}+1, n]}, |\mathcal{K}| = t\}$ . First, consider the subset of error vectors  $\mathcal{V}_2 = \{\rho \oplus \mathbf{1}_{\mathcal{K}} | \mathcal{K} \in \mathcal{P}_{[n]}, |\mathcal{K}| < t\}$ . By Property 1, we have that  $\mathcal{V}_2$  is covered by the patterns in  $\mathcal{R}_{\text{LW}} \setminus \{\rho\}$  with Hamming weight smaller than  $w_{\text{H}}(\rho)$ . Next, consider the subset of error vectors  $\mathcal{V}_3 = \{\rho \oplus \mathbf{1}_{\mathcal{K}} | \mathcal{K} \in \mathcal{P}_{[i_{\rho}^{\text{max}}]}, |\mathcal{K}| \leq t\}$ . These error vectors are covered by Property 1 since all patterns of the

same weight but with smaller binary representation and thus smaller logistic weights are also in  $\mathcal{R}_{\text{LW}} \setminus \{\rho\}$ . The error vectors in  $\mathcal{V}_1$  are not covered by any pattern in  $\mathcal{R}_{\text{LW}} \setminus \{\rho\}$  as the pattern  $\rho$  has by Definition 1 the largest logistic weight of a pattern with the same Hamming weight. Overall, it holds that  $\mathcal{V} = \mathcal{V}_1 \cup \mathcal{V}_2 \cup \mathcal{V}_3$  and we have that the additional error vectors covered by the pattern  $\rho$  are those in  $\mathcal{V}_1$ . ■

The probability that the transmitted codeword is in the list generated by the Chase-like algorithm with logistic weight patterns  $\mathcal{R}_{\text{LW}}$  can be calculated as stated in the following proposition.

**Proposition 1.** Let  $\mathcal{R}_{\text{LW}}$  be the set of logistic weight patterns as in Definition 1 with  $w_{\text{H}}^{\text{max}} = \max_{\rho \in \mathcal{R}_{\text{LW}}} w_{\text{H}}(\rho)$ . The probability that the transmitted codeword is in the list generated by the Chase-like algorithm is

$$P_{\text{LW}}(c \in \mathcal{L}) = P_{\text{BDD}} + \sum_{i=1}^{w_{\text{H}}^{\text{max}}} \sum_{\rho \in \mathcal{R}_i} P(e_{[i_{\rho}^{\text{max}}]} = \rho_{[i_{\rho}^{\text{max}}]} | \mathcal{E}_{t+i})P(\mathcal{E}_{t+i}), \quad (5)$$

where  $\mathcal{R}_w = \{\rho \in \mathcal{R}_{\text{LW}} | w_{\text{H}}(\rho) = w\}$ .

*Proof:* We show that the probability  $P_{\text{LW}}(c \in \mathcal{L})$  can be calculated with (5) by induction. Consider the pattern set  $\mathcal{R}_{\text{LW}} = \{\mathbf{0}\}$  with  $q = 1$ . We have  $P_{\text{LW}}(c \in \mathcal{L}) = P_{\text{BDD}}$  by (2). Assume that for a set of  $q$  logistic weight patterns  $\mathcal{R}_{\text{LW}}$  (5) holds. If we add one pattern  $\rho'$  with Hamming weight  $w' = w_{\text{H}}(\rho')$  such that  $|\mathcal{R}_{\text{LW}}| = q + 1$ , the additionally covered error patterns are stated in Lemma 1. The probability of these additionally covered error patterns is exactly  $P(e_{[i_{\rho'}^{\text{max}}]} = \rho'_{[i_{\rho'}^{\text{max}}]} | \mathcal{E}_{t+w'})P(\mathcal{E}_{t+w'})$ , which concludes the induction and the proof. ■

The conditional probability  $P(e_{[i_{\rho}^{\text{max}}]} = \rho_{[i_{\rho}^{\text{max}}]} | \mathcal{E}_{t+i})$  can be calculated using order statistics which is in detail described in Appendix A.

### B. List Error Rate by Covered Space Probability

Another way to estimate the list error rate of Chase-like algorithms is based on the probability of the covered space  $P_{\text{cov}}(\mathbf{y})$ . To calculate the average probability that the transmitted codeword  $c$  is in the list  $\mathcal{L}$ , a Monte Carlo simulation can be used such that

$$P_{\mathcal{R}}(c \in \mathcal{L}) = \mathbb{E}_{\mathbf{y}} [P_{\text{cov}}(\mathbf{y})] \approx \frac{1}{N} \sum_{i=1}^N \sum_{\mathbf{v} \in \mathcal{V}} P(\mathbf{v} | \mathbf{y})$$

for a sufficiently large number  $N$  of realizations of  $\mathbf{y}$  based on the law of large numbers. The advantage of this method is that it can be applied to any set of patterns  $\mathcal{R}$  without the need for a specific structure of the patterns. However, if the calculation of the overlap of individual patterns for the covered space probability is computationally too expensive, it can be more efficient to directly estimates  $P_{\mathcal{R}}(c \in \mathcal{L})$  via Monte Carlo simulation.

### C. List Error Rate by Monte Carlo Simulation

The direct way to compute the list error rate of Chase-like decoding is to perform a Monte Carlo simulation. This is done by simulating the transmission of codewords over the channel, running the Chase-like decoder, and checking whether the transmitted codeword appears in the list generated by the algorithm.

This method is straightforward and can be applied to any set of patterns  $\mathcal{R}$  without the need for a specific structure of the patterns. It is possible to obtain estimates of the block error rate (BLER) as well as the LER in the same simulation. However, it can be computationally expensive, especially for small error probabilities at high signal-to-noise-ratios (SNRs), as a large number of simulations may be required to obtain accurate estimates of the performance.

## IV. PATTERN DESIGNS FOR CHASE-LIKE DECODING

For a fixed number of patterns  $q$ , the optimal test pattern set  $\mathcal{R}_{\text{opt}}$ , i.e., the set of patterns that minimizes the LER, is defined as

$$\mathcal{R}_{\text{opt}} \triangleq \arg \min_{\mathcal{R} \subseteq \mathbb{F}_2^n} P_{\mathcal{R}}(\mathbf{c} \notin \mathcal{L}), \quad \text{s.t. } |\mathcal{R}_{\text{opt}}| = q.$$

However, finding  $\mathcal{R}_{\text{opt}}$  belongs to the class of maximizing submodular set functions which was acknowledged to be NP-hard [22]. Thus, the only way to obtain the optimal set of test patterns is exhaustive search, which is typically not feasible.

Therefore, we propose two design algorithms that find sets of good test patterns. Both construct  $\mathcal{R}$  iteratively, choosing from a set of candidate patterns.

### A. Generating Candidate Patterns

In [23], an algorithm was introduced that generates all vectors of the full space  $\mathbb{F}_2^n$  ordered according to a metric for a given realization  $\mathbf{y}$ . We use the algorithm to generate candidate patterns in decreasing metric, averaging over many realizations, and denote the algorithm as OCP (ordered candidate patterns), where  $\rho = \text{OCP}(i)$  is the pattern  $\rho$  with  $i$ -th largest metric.

It can be used to get the ordered patterns according to the probability of the Hamming ball of radius  $t$  around the pattern  $P(e \in \mathcal{B}_t(\rho))$ . We denote the algorithm that orders  $\mathbb{F}_2^n$  according to this as  $\text{OCP}_{\mathcal{B}_t(v)}$ . If ordering is performed with respect to  $P(e = \rho)$ , the corresponding generating algorithm is named  $\text{OCP}_v$ .

### B. Greedy Pattern Design

The best algorithm to maximize the coverage in polynomial time is a greedy algorithm [24]. For our setup, it works as described in the following. Until the target number of patterns  $q$  is reached, the greedy algorithm adds new patterns  $\rho$  to  $\mathcal{R}$  iteratively. The added pattern is chosen according to the rule that  $\rho$  improves the LER the most, i.e.,

$$\rho = \arg \min_{\mathbf{v} \in \mathbb{F}_2^n} P_{\mathcal{R} \cup \{\mathbf{v}\}}(\mathbf{c} \notin \mathcal{L}) = \arg \max_{\mathbf{v} \in \mathbb{F}_2^n} P_{\mathcal{R}}^{\text{add}}(\mathbf{v}).$$

Using  $\text{OCP}_{\mathcal{B}_t(v)}$ , the size of the search space can be significantly reduced. Having sequentially searched the first  $j$  patterns generated by  $\text{OCP}_{\mathcal{B}_t(v)}$ , let the best pattern found so far be  $\rho_{\text{best}}$ . Then, the pattern  $\rho_j = \text{OCP}_{\mathcal{B}_t(v)}(j)$  can yield larger added covered probability if and only if  $P_{\rho}^{\text{add}}(\rho_{\text{best}}) < P(e \in \mathcal{B}_t(\rho_j))$ . If this criterion is not fulfilled, no further patterns have to be considered.

However, even the greedy algorithm is computationally expensive for longer codes. For this reason, we propose a new heuristic design rule.

### C. Maximum Covering Pattern Design

A good set of test patterns should cover all most probable error vectors, i.e.,  $\min_{\rho \in \mathcal{R}} d_{\text{H}}(\rho, \text{OCP}_v(i)) \leq t$  for small  $i$ . Furthermore, the probability  $P(e = \rho)$  can be used as a proxy for  $P_{\mathcal{R}}^{\text{add}}(\rho)$ .

Based on these observations, we propose a pattern design named maximally covered ordered candidate (MCOC) as described in Algorithm 1. Iteratively, the  $i$ -th most likely pattern  $\rho = \text{OCP}(i)$  is considered. If it is not covered by the test patterns found so far,  $\arg \max_{\mathbf{v} \in \mathcal{B}_t(\rho)} P(\mathbf{v} = \mathbf{e})$  is added to  $\mathcal{R}$ .

---

**Algorithm 1:** Maximally Covering Ordered Candidate Patterns.

---

**Input :** SNR  $E_b/N_0$ , pattern number  $q$ , parameters  $(n, k, t)$ .  
**Output:** Set of patterns  $\mathcal{R}$ .

---

```

1  $\mathcal{R} \leftarrow \emptyset; i \leftarrow 1;$ 
2 while  $|\mathcal{R}| < q$  do
3    $\rho \leftarrow \text{OCP}_v(i);$  // next likely pattern
4   if  $\min_{\rho' \in \mathcal{R}} d_{\text{H}}(\rho, \rho') > t$  then
5     for  $j \leftarrow 1$  to  $i$  do
6        $\rho_j = \text{OCP}_v(j);$ 
7       if  $d_{\text{H}}(\rho, \rho_j) \leq t$  then
8          $\mathcal{R} \leftarrow \mathcal{R} \cup \{\rho_j\};$ 
9         break; // go to line 13
10      end
11    end
12  end
13   $i \leftarrow i + 1;$ 
14 end
15 return  $\mathcal{R}$ 

```

---

## V. RESULTS

In Fig. 1, the three methods, direct Monte Carlo, order statistics calculations and covered space probability, agree on the list error rates of the (128,120) extended Hamming code for 128 logistic weight patterns. This shows that all three methods are well suited to predict the list error rate.

Additionally, Fig. 1 shows the LER of four different test pattern sets with cardinality  $q = 16$  and  $q = 64$ . For  $q = 16$ , i.e.,  $p = 4$ , the Chase algorithm performs slightly worse than the logistic weights, greedy patterns and the MCOC patterns, which are approximately on par. For  $q = 64$ , the Chase-II decoder with  $p = 6$  performs much worse than the other patterns. There, we can see a slight gain of the greedy patterns over the MCOC patterns for high SNRs. The logistic weight

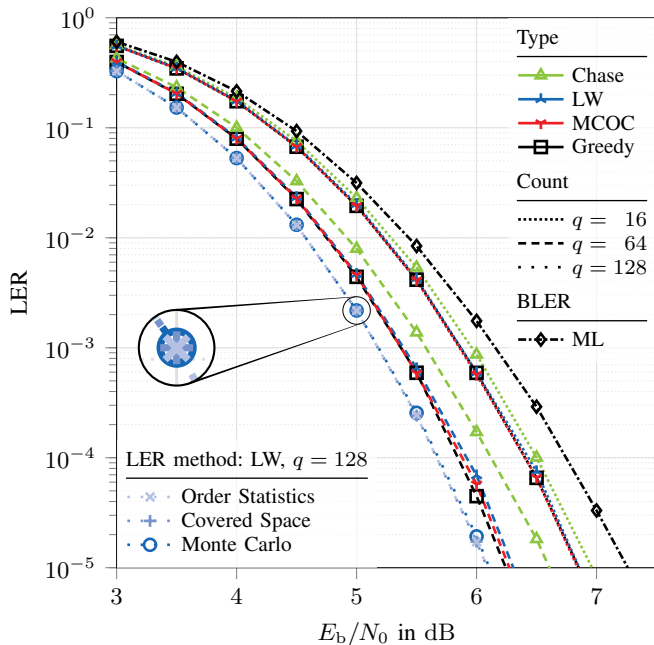


Fig. 1. List error rate of the (128,120) extended Hamming code decoded with different sets of patterns of size  $q \in \{16, 64, 128\}$ .

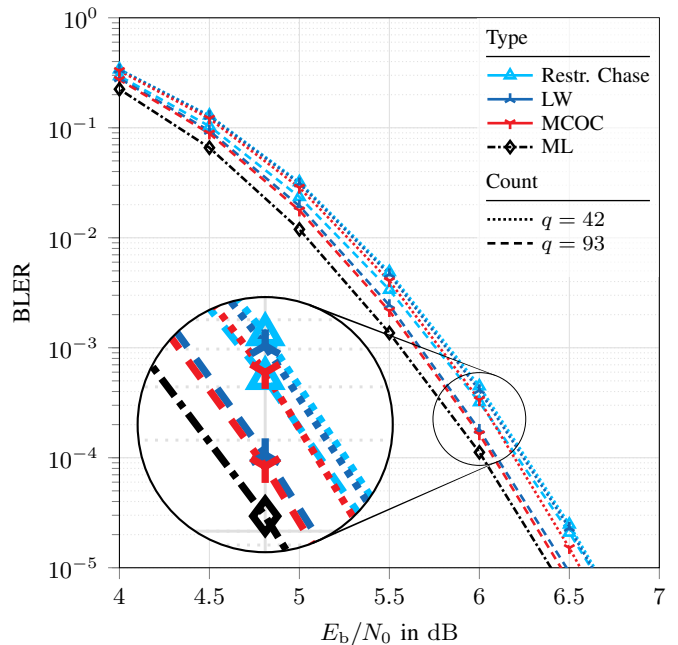


Fig. 2. Block error rate of the (256,239) extended BCH code decoded with  $q \in \{42, 93\}$  patterns for different pattern sets. The restricted Chase pattern sets are with  $p \in \{6, 8\}$  and  $w_H^{\max} = 3$ .

patterns have only a small performance decrease at LER  $10^{-4}$  of 0.1 dB compared to the greedy patterns. Since all of the considered patterns have a better LER than the ML BLER, they all exhibit near-ML performance.

Another code of interest is the (256, 239) extended BCH code used as a component code in oFEC [9]. The BLER for different sets of patterns is depicted in Fig. 2. Surprisingly, the MCOC patterns with  $q = 42$  perform better than the restricted Chase patterns with more than twice as many test patterns. The logistic weight patterns for  $q = 93$  are almost as good as our suggested set of patterns. Since  $q = 93$  restricted Chase patterns with  $p = 8$  and  $w_H^{\max} = 3$  are able to achieve the desired threshold for oFEC [25], we can assume that with MCOC patterns or logistic weight patterns the number of required decodings can be reduced. It was not possible to obtain a greedy set for this code in a reasonable time.

In Fig. 3, the LER is illustrated for a fixed SNR of 5.5 dB for the same BCH code but over different pattern designs and number of patterns. We see that for more patterns, the gap between our suggested design, logistic weight patterns and Chase variants grows larger.

## VI. CONCLUSION

We have discussed three different methods for evaluating the performance of test pattern sets for Chase-like decoding. All three give accurate estimations of the list error rate. In addition, we suggest an algorithm for finding test pattern sets which performs almost as good as test patterns found with the optimal algorithm in polynomial time.

Future work could aim to use the insights to design test pattern sets for iterative decoding of product codes and their generalizations.

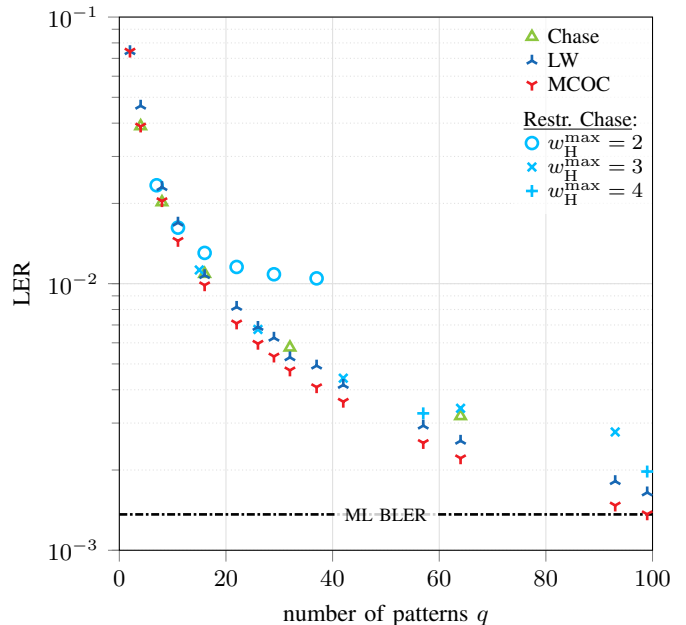


Fig. 3. List error rate over the number of patterns of different sets used to decode the (256,239) extended BCH code at an SNR of 5.5 dB.

## ACKNOWLEDGMENT

The authors would like to thank Benjamin Castellaz for pointing us to the methods for efficient order statistics calculations.

## REFERENCES

- [1] A. Hocquenghem, "Codes correcteurs d'erreurs," *Chiffres*, vol. 2, pp. 147–156, Sep. 1959.
- [2] R. C. Bose and D. K. Ray-Chaudhuri, "On a class of error correcting binary group codes," *Information and Control*, vol. 3, no. 1, pp. 68–79, Mar. 1960.
- [3] S. Lin and D. J. Costello, *Error Control Coding: Fundamentals and Applications*, 2nd ed. Pearson-Prentice Hall, 2004.
- [4] G. D. Forney Jr., *Concatenated Codes*, ser. Research Monograph. Cambridge, MA, USA: MIT Press, 1966, no. 37.
- [5] B. Matuz, E. B. Yacoub, and S. Calabrò, "Serially concatenated codes for data center networks," in *2025 13th International Symposium on Topics in Coding (ISTC)*, Aug. 2025, pp. 1–5.
- [6] B. P. Smith, A. Farhood, A. Hunt, F. R. Kschischang, and J. Lodge, "Staircase Codes: FEC for 100 Gb/s OTN," *J. Light. Technol.*, vol. 30, no. 1, pp. 110–117, Jan. 2012.
- [7] A. Y. Sukmadji, U. Martínez-Peñas, and F. R. Kschischang, "Zipper codes," *J. Light. Technol.*, vol. 40, no. 19, pp. 6397–6407, Oct. 2022.
- [8] M. Shehadeh, F. R. Kschischang, A. Y. Sukmadji, and W. Kingsford, "Higher-order staircase codes," *IEEE Trans. Inf. Theory*, vol. 71, no. 4, pp. 2517–2538, Apr. 2025.
- [9] M. A. Sluyski, "Open ROADM MSA 6.0 W B400G port digital specification (400G-800G)," Dec. 2023.
- [10] R. Pyndiah, "Near-optimum decoding of product codes: block turbo codes," *IEEE Trans. Commun.*, vol. 46, pp. 1003–1010, Aug. 1998.
- [11] D. Chase, "Class of algorithms for decoding block codes with channel measurement information," *IEEE Trans. Inf. Theory*, vol. 18, no. 1, pp. 170–182, Jan. 1972.
- [12] K. R. Duffy, W. An, and M. Médard, "Ordered reliability bits guessing random additive noise decoding," *IEEE Trans. Signal Process.*, vol. 70, pp. 4528–4542, 2022.
- [13] Y. Shen, W. Song, L. D. Blanc, Y. Ren, A. Balatsoukas-Stimming, A. Alvarado, and A. Burg, "Iterative logistic weight based chase decoder for open forward error correction," in *2025 Optical Fiber Communications Conference and Exhibition (OFC)*, Mar. 2025, pp. 1–3.
- [14] H. Tokushige, T. Koumoto, M. P. C. Fossorier, and T. Kasami, "Selection method of test patterns in soft-decision iterative bounded distance decoding algorithms," *IEICE Trans. Fundam.*, vol. E86-A, no. 10, pp. 2445–2451, Oct. 2003.
- [15] H. Tokushige, M. P. C. Fossorier, and T. Kasami, "A test pattern selection method for a joint bounded-distance and encoding-based decoding algorithm of binary codes," *IEEE Trans. Commun.*, vol. 58, no. 6, pp. 1601–1604, Jun. 2010.
- [16] G. Cohen, I. Honkala, S. Litsyn, and A. Lobstein, *Covering Codes*, ser. North-Holland Mathematical Library. Amsterdam, The Netherlands: Elsevier, 1997, vol. 54.
- [17] G. D. Forney Jr., "Generalized minimum distance decoding," *IEEE Trans. Inf. Theory*, vol. 12, no. 2, pp. 125–131, Apr. 1966.
- [18] D. Agrawal and A. Vardy, "Generalized minimum distance decoding in Euclidean space: performance analysis," *IEEE Trans. Inf. Theory*, vol. 46, no. 1, pp. 60–83, Jan. 2000.
- [19] M. P. C. Fossorier and S. Lin, "Error performance analysis for reliability-based decoding algorithms," *IEEE Trans. Inf. Theory*, vol. 48, no. 1, pp. 287–293, Jan. 2002.
- [20] X. He, L. Chen, and Y. Wu, "Performance analysis and enhanced chase decoding of GII-BCH codes," *IEEE Trans. Commun.*, vol. 73, no. 10, pp. 8647–8658, Oct. 2025.
- [21] T. Janz, S. Obermüller, A. Zunker, and S. ten Brink, "Soft-output from covered space decoding of product codes," in *2025 13th International Symposium on Topics in Coding (ISTC)*, Aug. 2025, pp. 1–5.
- [22] G. L. Nemhauser, L. A. Wolsey, and M. L. Fisher, "An analysis of approximations for maximizing submodular set functions—I," *Mathematical Programming*, vol. 14, no. 1, pp. 265–294, Dec. 1978.
- [23] A. Solomon, K. R. Duffy, and M. Médard, "Soft maximum likelihood decoding using GRAND," in *2020 IEEE International Conference on Communications (ICC)*, Jun. 2020, pp. 1–6.
- [24] U. Feige, "A threshold of  $\ln n$  for approximating set cover," *J. ACM*, vol. 45, no. 4, p. 634–652, Jul. 1998.
- [25] W. Wang, Z. Long, W. Qian, K. Tao, Z. Wei, S. Zhang, Z. Feng, Y. Xia, and Y. Chen, "Real-time FPGA investigation of potential FEC schemes for 800G-ZR/ZR+ forward error correction," *J. Light. Technol.*, vol. 41, no. 3, pp. 926–933, Feb. 2023.
- [26] H. A. David and H. N. Nagaraja, *Order Statistics*, 3rd ed. Hoboken, NJ, USA: Wiley, 2003.
- [27] C. P. Robert and G. Casella, *Monte Carlo Statistical Methods*, 2nd ed. Springer, 2004.
- [28] L. Devroye, *Non-Uniform Random Variate Generation*. New York, USA: Springer-Verlag, 1986.

APPENDIX A  
ORDER STATISTICS SETUP

The density functions  $f_c(x)$  and  $f_e(x)$  of the reliability  $\alpha_i$  for a correct hard decision at position  $i$  and a wrong hard decision at position  $i$ , respectively, are given by

$$f_c(x) = \begin{cases} \frac{q_\sigma(x+1)}{Q_\sigma(1)} & x \geq 0 \\ 0 & \text{otherwise} \end{cases}$$

$$f_e(x) = \begin{cases} \frac{q_\sigma(x-1)}{1-Q_\sigma(1)} & x \geq 0 \\ 0 & \text{otherwise} \end{cases}$$

with

$$q_\sigma(x) = \frac{1}{\sqrt{2\pi\sigma^2}} e^{-\frac{x^2}{2\sigma^2}} \text{ and } Q_\sigma(x) = \int_x^\infty q_\sigma(t) dt.$$

The corresponding cumulative distribution functions are denoted by  $F_c(x)$  and  $F_e(x)$ , respectively, and are given by

$$F_c(x) = \begin{cases} \frac{Q_\sigma(1)-Q_\sigma(x+1)}{Q_\sigma(1)} & x \geq 0 \\ 0 & \text{otherwise} \end{cases}$$

$$F_e(x) = \begin{cases} \frac{1-Q_\sigma(1)-Q_\sigma(x-1)}{1-Q_\sigma(1)} & x \geq 0 \\ 0 & \text{otherwise.} \end{cases}$$

After transmission, the hard decision  $\hat{\mathbf{y}}$  is erroneous at  $b$  positions. The  $b$  reliabilities of positions where the hard decision is wrong are denoted by  $\beta_{b,(1)} \leq \beta_{b,(2)} \leq \dots \leq \beta_{b,(b)}$ . Similarly, the  $n-b$  reliabilities of positions where the hard decision is correct are denoted by  $\gamma_{n-b,(1)} \leq \gamma_{n-b,(2)} \leq \dots \leq \gamma_{n-b,(n-b)}$ . The probability density functions of  $\beta_{b,(i)}$  and  $\gamma_{n-b,(j)}$  are order statistics of the above given functions. Following [26], they are given by

$$f_{\beta_{b,(i)}}(x) = \Theta(b, i) f_e(x) [F_e(x)]^{i-1} [1 - F_e(x)]^{b-i}$$

$$f_{\gamma_{n-b,(j)}}(x) = \Theta(n-b, j) f_c(x) [F_c(x)]^{j-1} [1 - F_c(x)]^{n-b-j},$$

with  $\Theta(m, n)$  defined as  $\Theta(m, n) = m \binom{m-1}{n-1}$ . Consider the subsets  $\mathcal{I} = \{i_1, \dots, i_\mu\} \subseteq [b]$  with  $|\mathcal{I}| = \mu$  and  $\mathcal{J} = \{j_1, \dots, j_\nu\} \subseteq [n-b]$  with  $|\mathcal{J}| = \nu$ . We denote the joint probability density functions of all  $\beta_{b,(i)}$  with  $i \in \mathcal{I}$  and of all  $\gamma_{n-b,(j)}$  with  $j \in \mathcal{J}$  in short by  $f_{\beta_{b,\mathcal{I}}}(\mathbf{x}_{\mathcal{I}}) \triangleq f_{\{\beta_{b,(i)}\}_{i \in \mathcal{I}}}(\{x_i\}_{i \in \mathcal{I}})$  and  $f_{\gamma_{n-b,\mathcal{J}}}(\mathbf{x}_{\mathcal{J}}) \triangleq f_{\{\gamma_{n-b,(j)}\}_{j \in \mathcal{J}}}(\{x_j\}_{j \in \mathcal{J}})$ . They can be calculated as in [26] by

$$f_{\beta_{b,\mathcal{I}}}(\mathbf{x}_{\mathcal{I}}) = b! \left[ \prod_{u \in \mathcal{I}} f_e(x_u) \right] \prod_{\ell=0}^{\mu} \left( \frac{[F_e(x_{i_{\ell+1}}) - F_e(x_{i_\ell})]^{i_{\ell+1} - i_\ell - 1}}{(i_{\ell+1} - i_\ell - 1)!} \right) \quad (6)$$

with  $x_0 = 0$ ,  $x_{\nu+1} = \infty$ ,  $n_0 = 0$  and  $n_{\nu+1} = b+1$  as well as

$$f_{\gamma_{n-b,\mathcal{J}}}(\mathbf{x}_{\mathcal{J}}) = m! \left[ \prod_{u \in \mathcal{J}} f_c(x_u) \right] \prod_{\ell=0}^{\nu} \left( \frac{[F_c(x_{j_{\ell+1}}) - F_c(x_{j_\ell})]^{j_{\ell+1} - j_\ell - 1}}{(j_{\ell+1} - j_\ell - 1)!} \right) \quad (7)$$

with  $m = n - b$ ,  $x_0 = 0$ ,  $x_{\mu+1} = \infty$ ,  $i_0 = 0$ , and  $i_{\mu+1} = n - b + 1$ .

We now have all order statistics definitions to show how the terms from Appendix III-A can be calculated.

CONSTRAINT CONDITIONAL PROBABILITY CALCULATION

In (3), (4), and (5), two types of probabilities need to be calculated. The first is the probability of  $i$  transmission errors  $P(\mathcal{E}_i)$  which is determined by (1). The second are conditional probabilities imposing a constraint on the error vector  $e$  given the event  $\mathcal{E}_i$  that  $i$  transmission errors have occurred. We can calculate them using the above stated order statistics functions which assume that the event  $\mathcal{E}_b$  has occurred.

The conditional probability  $P(w_H(e_{[p]}) = b - t | \mathcal{E}_b)$  is required to get the LER of Chase-II and restricted Chase decoding patterns as in (3), (4). The probability captures the event in which  $b-t$  of the  $b$  errors fall within the  $p$  least reliable positions. In other words, the reliabilities  $\beta_{b,(1)}, \dots, \beta_{b,(b-t)}$  have a smaller absolute value than the reliabilities in the positions  $[p+1, n]$ . The reliability with smallest absolute value in these positions without an error is  $\gamma_{n-b,(p+1-(b-t))}$ . Therefore, the event is captured by  $\beta_{b,(b-t)} \leq \gamma_{n-b,(p+1-(b-t))}$  and it holds that

$$P(w_H(e_{[p]}) = b - t | \mathcal{E}_b) = \int_0^\infty f_{\beta_{b,(b-t)}}(x) \left( \int_x^\infty f_{\gamma_{n-b,(p+t+1-b)}}(y) dy \right) dx,$$

as also given in [18], [19].

Before explaining how to calculate the conditional probability  $P(e_{[i_\rho^{\max}]} = \rho_{[i_\rho^{\max}]} | \mathcal{E}_{t+i})$ , it is helpful to provide an example.

**Example 1.** Consider a toy example where the (7, 4) Hamming code with  $t = 1$  is decoded with  $q = 19$  logistic weight test patterns<sup>1</sup>. The pattern set  $\mathcal{R}_{\text{LW}}$  includes all patterns with  $w_L(\rho) \leq 8$ , which are

$$\begin{aligned} & [0, 0, 0, 0, 0, 0, 0], [1, 0, 0, 0, 0, 0, 0], [0, 1, 0, 0, 0, 0, 0], \\ & [0, 0, 1, 0, 0, 0, 0], [0, 0, 0, 1, 0, 0, 0], [0, 0, 0, 0, 1, 0, 0], \\ & [0, 0, 0, 0, 0, 1, 0], [0, 0, 0, 0, 0, 0, 1], [1, 1, 0, 0, 0, 0, 0], \\ & [1, 0, 1, 0, 0, 0, 0], [0, 1, 1, 0, 0, 0, 0], [1, 0, 0, 1, 0, 0, 0], \\ & [0, 1, 0, 1, 0, 0, 0], [0, 0, 1, 1, 0, 0, 0], [1, 0, 0, 0, 1, 0, 0], \\ & [0, 1, 0, 0, 1, 0, 0], [1, 0, 0, 0, 0, 1, 0], [1, 1, 1, 0, 0, 0, 0], \\ & [1, 1, 0, 1, 0, 0, 0]. \end{aligned}$$

We consider the additional probability of the last pattern, i.e.,  $P_{\mathcal{R}'_{\text{LW}}}^{\text{add}}(\rho)$  with  $\rho = [1, 1, 0, 1, 0, 0, 0]$  and  $\mathcal{R}'_{\text{LW}} = \mathcal{R}_{\text{LW}} \setminus \{\rho\}$ . From Proposition 1 and (5), we know that the additional probability is  $P(e_{[i_\rho^{\max}]} = \rho_{[i_\rho^{\max}]} | \mathcal{E}_{t+i}) P(\mathcal{E}_{t+i})$  with  $t = 1$ ,  $i_\rho^{\max} = 4$ ,  $i = w_H(\rho) = 3$ , thus

$$P_{\mathcal{R}'_{\text{LW}}}^{\text{add}}(\rho) = P(e_{[4]} = \rho_{[4]} | \mathcal{E}_5) P(\mathcal{E}_5).$$

<sup>1</sup>The avid reader may notice that using 19 test patterns to decode a perfect code with 16 codewords does not make sense. However, this is just a toy example for illustration purposes.

The probability  $P(\mathcal{E}_5)$  can be calculated with (1). To calculate the conditional probability  $P(e_{[4]} = \rho_{[4]} | \mathcal{E}_5)$ , we consider the order statistics setup, where  $b = 5$  transmission errors have occurred. The condition  $e_{[4]} = \rho_{[4]}$  can then be translated to conditions on the corresponding ordered reliabilities  $\beta, \gamma$  which were flipped and which were not flipped, respectively. For the pattern  $\rho$ , the conditions are given by

$$\begin{array}{ccccccccc} & & & & & & & & \gamma_{2,(2)} \\ \beta_{5,(1)} & \leq & \beta_{5,(2)} & \leq & \gamma_{2,(1)} & \leq & \beta_{5,(3)} & \leq & \beta_{5,(4)} \\ & & & & & & & & \beta_{5,(5)} \\ [1, & & 1, & & 0, & & 1, & & 0, 0, 0]. \end{array}$$

The desired constraint  $e_{[4]} = \rho_{[4]}$  can only constrain reliabilities in the positions 1 to 4. The order of the last three reliabilities  $\gamma_{2,(2)}, \beta_{5,(4)}$  and  $\beta_{5,(5)}$  does not play a role since the condition  $e_{[4]} = \rho_{[4]}$  does not cover these positions. The additional condition on the non-zero position with largest index, i.e., position 4, is given by the reliability with smallest absolute value in positions [5, 7] and that was not flipped. Here, this is  $\gamma_{2,(2)}$ . Some of the conditions are fulfilled by definition of order statistics, e.g.,  $\beta_{5,(1)} \leq \beta_{5,(2)}$ . Overall, the three conditions  $\beta_{5,(2)} \leq \gamma_{2,(1)}$ ,  $\gamma_{2,(1)} \leq \beta_{5,(3)}$  and  $\beta_{5,(3)} \leq \gamma_{2,(2)}$  have to hold. We denote them by a set of conditions  $\mathcal{F}$ , i.e.,

$$\mathcal{F} = \{\beta_{5,(2)} \leq \gamma_{2,(1)}, \gamma_{2,(1)} \leq \beta_{5,(3)}, \beta_{5,(3)} \leq \gamma_{2,(2)}\}$$

The space of non-negative numbers for which the conditions in  $\mathcal{F}$  hold are denoted by  $\mathbb{R}_{\geq 0, \mathcal{F}}^3$ . We then have

$$P(e_{[4]} = \rho_{[4]} | \mathcal{E}_5) = \int_{\mathbb{R}_{\geq 0, \mathcal{F}}^3} f_{\beta_{5,\{2,3\}}}(\mathbf{x}_{\{2,3\}}) f_{\gamma_{2,(1)}}(y) d\mathbf{x}_{\{2,3\}} dy,$$

where  $f_{\beta_{5,\{2,3\}}}(\mathbf{x}_{\{2,3\}})$  is the joint probability density function of  $\beta_{5,(2)}$  and  $\beta_{5,(3)}$ . and  $f_{\gamma_{2,(1)}}(y)$  the probability density function of  $\gamma_{2,(1)}$ .

Keeping this example in mind, we can now generalize the calculation of  $P(e_{[i_{\rho}^{\max}]} = \rho_{[i_{\rho}^{\max}]} | \mathcal{E}_{t+w})$  for a pattern  $\rho \in \mathcal{R}_{\text{LW}} \setminus \{\mathbf{0}\}$  with Hamming weight  $w > 0$ .

**Calculation Rule.** Consider a pattern  $\rho \in \mathcal{R}_{\text{LW}} \setminus \{\mathbf{0}\}$  with Hamming weight  $w > 0$  as in Proposition 1 within the order statistics setup with  $b = t + w$  transmission errors. Denote by  $\mathcal{F}$  the non-trivial conditions imposed by  $e_{[i_{\rho}^{\max}]} = \rho_{[i_{\rho}^{\max}]}$  on the variables in the positions  $[i_{\rho}^{\max}]$ . If  $\rho_i = 1$ , the position  $i$  corresponds to an order statistics variable  $\beta_b$ . If  $\rho_i = 0$ , the position  $i$  corresponds to an order statistics variable  $\gamma_{n-b}$ . Additionally, we have a constraint on the position  $i_{\rho}^{\max}$  corresponding to  $\beta_{b,(w)}$  and  $\gamma_{n-b,(i_{\rho}^{\max}-w+1)}$ , following from the fact that of the  $[i_{\rho}^{\max}]$  positions  $i_{\rho}^{\max} - w$  are not flipped. Thus, the smallest not erroneous position outside  $[i_{\rho}^{\max}]$  has the reliability  $\gamma_{n-b,(i_{\rho}^{\max}-w+1)}$ . The indices of the order statistics variables  $\beta$  and  $\gamma$  that are constraint by  $\mathcal{F}$  are denoted by  $\mathcal{I}_{\mathcal{F}}$  and  $\mathcal{J}_{\mathcal{F}}$ , respectively. We define  $d_{\mathcal{F}} \triangleq |\mathcal{I}_{\mathcal{F}}| + |\mathcal{J}_{\mathcal{F}}|$ , which is the total number of constraint positions. The conditional

probability  $P(e_{[i_{\rho}^{\max}]} = \rho_{[i_{\rho}^{\max}]} | \mathcal{E}_{t+w})$  can then be calculated by

$$\int_{\mathbb{R}_{\geq 0, \mathcal{F}}^{d_{\mathcal{F}}}} f_{\beta_{b, \mathcal{I}_{\mathcal{F}}}}(\mathbf{x}_{\mathcal{I}_{\mathcal{F}}}) f_{\gamma_{n-b, \mathcal{J}_{\mathcal{F}}}}(\mathbf{y}_{\mathcal{J}_{\mathcal{F}}}) d\mathbf{x}_{\mathcal{I}_{\mathcal{F}}} d\mathbf{y}_{\mathcal{J}_{\mathcal{F}}}, \quad (8)$$

where  $\mathbb{R}_{\geq 0, \mathcal{F}}^{d_{\mathcal{F}}}$  denotes the subset of  $\mathbb{R}_{\geq 0}^{d_{\mathcal{F}}}$  for which the conditions  $\mathcal{F}$  are fulfilled. The joint probability density functions  $f_{\beta_{b, \mathcal{I}_{\mathcal{F}}}}(\mathbf{x}_{\mathcal{I}_{\mathcal{F}}})$  and  $f_{\gamma_{n-b, \mathcal{J}_{\mathcal{F}}}}(\mathbf{y}_{\mathcal{J}_{\mathcal{F}}})$  are the ones defined in (6) and (7).

## EFFICIENT MONTE CARLO INTEGRATION FOR ORDER STATISTICS

Solving multidimensional integrals, such as the ones in (8), numerically based on the multidimensional functions is complex. Therefore, we calculate the integral more efficiently using Monte Carlo integration [27]. Assume that we can sample from the joint distributions  $f_{\mathcal{I}_{\mathcal{F}}}(\mathbf{x}_{\beta})$  and  $f_{\mathcal{J}_{\mathcal{F}}}(\mathbf{y}_{\gamma})$ . We can then estimate the probability via Monte Carlo simulation where in each step we sample from the joint distributions and check whether the conditions  $\mathcal{F}$  are fulfilled. The probability is then the number of tries where  $\mathcal{F}$  was fulfilled over the number of overall tries.

Sampling from the joint distributions can be done using the following property from [28]. The order statistics  $x_{(1)} \leq \dots \leq x_{(n)}$  that correspond to the sequence  $x_1, \dots, x_n$  of i.i.d. random variables with cumulative distribution function (CDF)  $F$  can be generated as

$$F^{-1}(u_{(1)}), \dots, F^{-1}(u_{(n)}),$$

where  $F^{-1}$  is the inverse CDF and  $u_{(1)} \leq \dots \leq u_{(n)}$  are order statistics from the uniform distribution on the interval  $[0, 1]$ . The inversion of the CDFs  $F_e$  and  $F_c$  can be implemented efficiently as well as sampling order statistics of the uniform distribution via an efficient built-in sampling from the beta distribution.